Search Notes			

Application No.	Applicant(s)	,
10/620,446	TSENG ET AL.	
Examiner	Art Unit	
Stephen W. Smoot	2813	

SEARCHED				
Class	Subclass	Date	Examiner	
438	4	11/10/2004	sws	
438	15	11/10/2004	sws	
438	17	11/10/2004	sws	
438	18	11/10/2004	sws	
438	107	11/10/2004	sws	
438	113	11/10/2004	sws	
438	122	11/10/2004	sws	
438	124	11/10/2004	sws	
438	126	11/10/2004	sws	
438	127	11/10/2004	sws	
438	460	11/10/2004	sws	

TMI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
					
		<u>. </u>			

SEARCH NOT (INCLUDING SEARCH	-) .
	DATE	EXMR
Key Words: Chip Carrier - MCM, PCB, PWB, Memory Module, SIMM; Contact, Terminal, Lead, Electrode, Connector, Finger - Gold;	11/12/2004	I.W.L sws
Test, Evaluate - Repair, Replace, Restore; KGD - Known Good Die; Laser; Metal Shield - Heat Sink.	11/12/2004	\$.1) & sws
		:
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	11/12/2004	8,W. S sws